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Title of Change:	Qualification of Bucheon 8inch as an additional Wafer FAB facility for Auto Non Punch Through Trench IGBT technology.			
Proposed Changed Material First Ship Date:	04 Nov 2021 or earlier if approved by customer			
Current Material Last Order Date:	N/A Orders received after the Current Material Last Order Date expiration are to be considered orders for new changed material as described in this PCN. Orders for current (unchange material after this date will be per mutual agreement and current material invento availability.			
Current Material Last Delivery Date:	N/A The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory			
Product Category:	Active components – Integrated circuits			
Contact information:	Contact your local ON Semiconductor Sales Office or Daniel.Jeon@onsemi.com			
PCN Samples Contact:	Contact your local ON Semiconductor Sales Office to place sample order or <pcn.samples@onsemi.com>. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.</pcn.samples@onsemi.com>			
Sample Availability Date:	N/A			
PPAP Availability Date:	N/A			
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or Choonbae.Park@onsemi.com			
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. The change will be implemented at 'Proposed Change Material First Ship Date' in compliance to J-STD-46 or ZVEI, or earlier upon customer approval, or per our signed agreements. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com.			
Change Category	·			
Category	Type of Change			
Process - Wafer Production	New wafer diameter			
Description and Purpose:	·			

Additional qualification of BK 8inch for Auto Non Punch Through Trench Insulated Gate Bipolar Transistor technology for Intelligent Power Module, only qualified wafer size, 8inch. No change in assembly and test.

It is for capacity constrain solution.

There is no material change and marking change

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Reason /	Motivation for Change:	Capacity improvement					
Anticipated impact on fit, form, function, reliability, product safety or manufacturability:		The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded.					
,		No anticipated impacts.					
Sites Affe	cted:						
ON Semic	I Semiconductor Sites		External Foundry/	Subcon Sites			
ON Semico	nductor Bucheon, Korea		None				
Marking o Change:	of Parts/ Traceability of	Marking is same / trace by date code.					
•	E NAME : NFVA23512NP2T						
•	49, 70956, 74197						
RMS: 709	49, 70956, 74197	Condition		Interval	Lot 1	Lot 2	Lot 2
RMS: 709 PKG: ASPI Test HTRB	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100	*** Tj = 125°C, Vce	e=1200V	1008 hrs	0/26	0/26	0/26
RMS: 709 PKG: ASPI Test HTRB H3TRB	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100	*** Tj = 125°C, Vce 85C, 85%RH, Vce	e=1200V e=100V	1008 hrs 1008 hrs	0/26 0/26	0/26 0/26	0/26 0/26
RMS: 709 PKG: ASPI Test HTRB H3TRB HTGB+	49, 70956, 74197 M34 <u>Specification</u> AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test	e=1200V =100V ed with TO3P)	1008 hrs 1008 hrs 1008 hrs	0/26 0/26 0/77	0/26 0/26 0/77	0/26 0/26 0/77
RMS: 709 PKG: ASPI Test HTRB H3TRB HTGB+ HTGB-	49, 70956, 74197 M34 <u>Specification</u> AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test	=1200V =100V ed with TO3P) ted with TO3P)	1008 hrs 1008 hrs 1008 hrs 1008 hrs	0/26 0/26 0/77 0/39	0/26 0/26 0/77 0/39	0/26 0/26 0/77 0/39
RMS: 709 PKG: ASPI Test HTRB H3TRB HTGB+	49, 70956, 74197 M34 <u>Specification</u> AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n	e=1200V e=100V ed with TO3P) ed with TO3P) o bias	1008 hrs 1008 hrs 1008 hrs	0/26 0/26 0/77	0/26 0/26 0/77	0/26 0/26 0/77
RMS: 709 PKG: ASPI Test HTRB H3TRB HTGB+ HTGB-	49, 70956, 74197 M34 <u>Specification</u> AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C Transition 20min max in on	e=1200V e=100V ed with TO3P) ed with TO3P) o bias e chamber equip.	1008 hrs 1008 hrs 1008 hrs 1008 hrs	0/26 0/26 0/77 0/39	0/26 0/26 0/77 0/39	0/26 0/26 0/77 0/39
RMS: 709 PKG: ASPI HTRB H3TRB HTGB+ HTGB- UHAST	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324 AECQ101/Q100	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C	=1200V ed with TO3P) ted with TO3P) o bias e chamber equip. p-air	1008 hrs 1008 hrs 1008 hrs 1008 hrs 96 hrs	0/26 0/26 0/77 0/39 0/77	0/26 0/26 0/77 0/39 0/77	0/26 0/26 0/77 0/39 0/77
RMS: 709 PKG: ASPI HTRB HTRB HTGB+ HTGB- uHAST TC	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324 AECQ101/Q100 AECQ101/Q100	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C Transition 20min max in on -40~125C, air-to Transition 30sec max, dwell m	=1200V ed with TO3P) ted with TO3P) o bias e chamber equip. p-air in 15min at min/max	1008 hrs 1008 hrs 1008 hrs 1008 hrs 96 hrs 1000cyc	0/26 0/26 0/77 0/39 0/77 0/77 0/77	0/26 0/26 0/77 0/39 0/77 0/77	0/26 0/26 0/77 0/39 0/77 0/77 0/77
RMS: 709 PKG: ASPP HTRB HTRB HTGB+ HTGB- uHAST TC TS	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324 AECQ101/Q100 AECQ101/Q100 AQG324, AECQ101/Q100	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C Transition 20min max in on -40~125C, air-to Transition 30sec max, dwell m temp	e chamber equip. co-air in 15min at min/max Tjmax 155	1008 hrs 1008 hrs 1008 hrs 1008 hrs 96 hrs 1000cyc 1000cyc	0/26 0/26 0/77 0/39 0/77 0/77 0/77 Faile	0/26 0/26 0/77 0/39 0/77 0/77 0/77	0/26 0/26 0/77 0/39 0/77 0/77 0/77
RMS: 709 PKG: ASPI HTRB H3TRB HTGB+ HTGB- uHAST TC TS PCsec1	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324 AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101/Q100	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C Transition 20min max in on -40~125C, air-to Transition 30sec max, dwell m temp 4 sec ON , dTj 100C	e=1200V ed with TO3P) ed with TO3P) o bias e chamber equip. o-air in 15min at min/max Tjmax 155	1008 hrs 1008 hrs 1008 hrs 1008 hrs 1008 hrs 96 hrs 1000cyc 1000cyc Test to fail	0/26 0/27 0/39 0/77 0/77 0/77 6/77 Faile	0/26 0/27 0/39 0/77 0/77 0/77 0/77	0/26 0/26 0/77 0/39 0/77 0/77 0/77 28Kcyc 8Kcyc
RMS: 709 PKG: ASPP HTRB HTRB HTGB+ HTGB- UHAST TC TS PCsec1 PCsec2	49, 70956, 74197 M34 Specification AQG324, AECQ101/Q100 AQG324, AECQ101/Q100 AQG324, AECQ101 AQG324 AECQ101/Q100 AQG324, AECQ101/Q100 AQG324 AQG324 AQG324	*** Tj = 125°C, Vce 85C, 85%RH, Vce Tj 150C, Vges=20V (test Tj 150C, Vges=-20V (test 130C/85%RH, n -40~125C Transition 20min max in on -40~125C, air-to Transition 30sec max, dwell m temp 4 sec ON , dTj 100C 4sec On, dTj 140C T	e chamber equip. co-air in 15min at min/max Tjmax 155 Tjmax 165	1008 hrs 1008 hrs 1008 hrs 1008 hrs 96 hrs 1000cyc 1000cyc Test to fail Test to fail	0/26 0/27 0/39 0/77 0/77 0/77 0/77 Faile Fail	0/26 0/27 0/39 0/77 0/77 0/77 ed from 12	0/26 0/27 0/39 0/77 0/77 0/77 28Kcyc 8Kcyc 4Kcyc

NOTE: AEC-1pager is attached.

To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
- 4. Then click on the attached file/s

Electrical Characteristics Summary:

Electrical characteristics are not impacted.



List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Current Part Number	New Part Number	Qualification Vehicle		
NFVA25012NP2T	NA	NFVA25012NP2T		
NFVA23512NP2T	NA	NFVA25012NP2T		
NFVA22512NP2T	NA	NFVA25012NP2T		